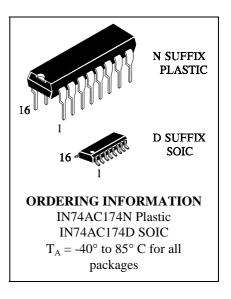
IN74AC174

Hex D Flip-Flop with Common Clock and Reset High-Speed Silicon-Gate CMOS

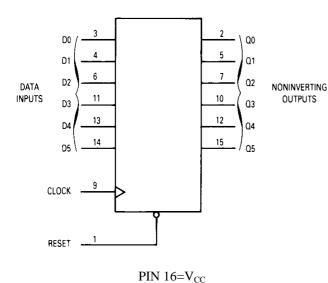
The IN74AC174 is identical in pinout to the LS/ALS174, HC/HCT174. The device inputs are compatible with standard CMOS outputs; with pullup resistors, they are compatible with LS/ALS outputs.

This device consists of six D flip-flops with common Clock and Reset inputs. Each flip-flop is loaded with a low-to-high transition of the Clock input. Reset is asynchronous and active-low.

- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 2.0 to 6.0 V
- Low Input Current: 1.0 μA; 0.1 μA @ 25°C
- High Noise Immunity Characteristic of CMOS Devices
- Outputs Source/Sink 24mA



LOGIC DIAGRAM



PIN 8 = GND

PIN ASSIGNMENT

RESET [1●	16	v_{cc}
Q0 [2	15	Q5
D0 [3	14	D5
D1 [4	13	D4 □
Q 1 [5	12	Q 4
D2 [6	11	D3
Q2 [7	10	Q3
GND [8	9	CLOCK

FUNCTION TABLE

Inputs			Output
Reset	Clock	D	Q
L	X	X	L
Н		Н	Н
Н		L	L
Н	L	X	no change
Н		X	no change

X = Don't care



MAXIMUM RATINGS*

Symbol	Parameter	Value	Unit
V_{CC}	DC Supply Voltage (Referenced to GND)	-0.5 to +7.0	V
V_{IN}	DC Input Voltage (Referenced to GND)	-0.5 to V _{CC} +0.5	V
V _{OUT}	DC Output Voltage (Referenced to GND)	-0.5 to V _{CC} +0.5	V
I_{IN}	DC Input Current, per Pin	±20	mA
I_{OUT}	DC Output Sink/Source Current, per Pin	±50	mA
I_{CC}	DC Supply Current, V _{CC} and GND Pins	±50	mA
P_{D}	Power Dissipation in Still Air, Plastic DIP+ SOIC Package+	750 500	mW
Tstg	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature, 1 mm from Case for 10 Seconds (Plastic DIP or SOIC Package)	260	°C

^{*}Maximum Ratings are those values beyond which damage to the device may occur. Functional operation should be restricted to the Recommended Operating Conditions.

SOIC Package: : - 7 mW/°C from 65° to 125°C

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Max	Unit
V_{CC}	DC Supply Voltage (Referenced to GND)	2.0	6.0	V
V_{IN}, V_{OUT}	DC Input Voltage, Output Voltage (Referenced to GND)	0	V_{CC}	V
T_{J}	Junction Temperature (PDIP)		140	°C
T_A	Operating Temperature, All Package Types		+85	°C
I_{OH}	Output Current - High		-24	mA
I_{OL}	Output Current - Low		24	mA
t _r , t _f	Input Rise and Fall Time * $V_{CC} = 3.0 \text{ V}$ (except Schmitt Inputs) $V_{CC} = 4.5 \text{ V}$ $V_{CC} = 5.5 \text{ V}$	0 0 0	150 40 25	ns/V

 $^{^*}V_{IN}\,$ from 30% to 70% $V_{CC}\,$

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{IN} and V_{OUT} should be constrained to the range $GND \leq (V_{IN} \text{ or } V_{OUT}) \leq V_{CC}$.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.



⁺Derating - Plastic DIP: - 10 mW/°C from 65° to 125°C

DC ELECTRICAL CHARACTERISTICS(Voltages Referenced to GND)

			V_{CC}	Guarante	Guaranteed Limits	
Symbol	Parameter	Test Conditions	V	25 °C	-40°C to 85°C	Unit
V_{IH}	Minimum High-Level Input Voltage	V_{OUT} =0.1 V or V_{CC} -0.1 V	3.0 4.5 5.5	2.1 3.15 3.85	2.1 3.15 3.85	V
V_{IL}	Maximum Low - Level Input Voltage	V _{OUT} =0.1 V or V _{CC} -0.1 V	3.0 4.5 5.5	0.9 1.35 1.65	0.9 1.35 1.65	V
V_{OH}	Minimum High-Level Output Voltage	I _{OUT} ≤ -50 μA	3.0 4.5 5.5	2.9 4.4 5.4	2.9 4.4 5.4	V
		* V _{IN} =V _{IH} or V _{IL} I_{OH} =-12 mA I_{OH} =-24 mA I_{OH} =-24 mA	3.0 4.5 5.5	2.56 3.86 4.86	2.46 3.76 4.76	
V_{OL}	Maximum Low-Level Output Voltage	$I_{OUT} \le 50 \mu A$	3.0 4.5 5.5	0.1 0.1 0.1	0.1 0.1 0.1	V
		* V _{IN} =V _{IH} or V _{IL} I_{OL} =12 mA I_{OL} =24 mA I_{OL} =24 mA	3.0 4.5 5.5	0.36 0.36 0.36	0.44 0.44 0.44	
I_{IN}	Maximum Input Leakage Current	V _{IN} =V _{CC} or GND	5.5	±0.1	±1.0	μА
I_{OLD}	+Minimum Dynamic Output Current	V _{OLD} =1.65 V Max	5.5		75	mA
I_{OHD}	+Minimum Dynamic Output Current	V _{OHD} =3.85 V Min	5.5		-75	mA
I_{CC}	Maximum Quiescent Supply Current (per Package)	V _{IN} =V _{CC} or GND	5.5	8.0	80	μΑ

^{*} All outputs loaded; thresholds on input associated with output under test.

Note: I_{IN} and I_{CC} @ 3.0 V are guaranteed to be less than or equal to the respective limit @ 5.5 V V_{CC}



⁺Maximum test duration 2.0 ms, one output loaded at a time.

$\textbf{AC ELECTRICAL CHARACTERISTICS}(C_L = 50 pF, Input \ t_i = t_f = 3.0 \ ns)$

		V_{CC}^{*}	(Guaranteed Limits			
Symbol	Parameter	V	25 °C		-40°C to 85°C		Unit
			Min	Max	Min	Max	
\mathbf{f}_{\max}	Maximum Clock Frequency (Figure 1)	3.3 5.0	90 100		70 100		MHz
t _{PLH}	Propagation Delay, Clock to Q (Figure 1)	3.3 5.0	2.0 1.5	11.5 8.5	1.5 1.0	12.5 9.5	ns
t _{PHL}	Propagation Delay, Clock to Q (Figure 1)	3.3 5.0	2.0 1.5	11.0 8.0	1.5 1.0	12.0 9.0	ns
t _{PHL}	Propagation Delay, Reset to Q (Figure 2)	3.3 5.0	2.5 1.5	11.5 9.0	2.0 1.5	12.5 10.5	ns
C_{IN}	Maximum Input Capacitance	5.0	4	.5	4.	5	pF

		Typical @25°C,V _{CC} =5.0 V	
C_{PD}	Power Dissipation Capacitance	85	pF

^{*}Voltage Range 3.3 V is 3.3 V ± 0.3 V Voltage Range 5.0 V is 5.0 V ± 0.5 V

$\textbf{TIMING REQUIREMENTS}(C_L = 50 pF, Input \ t_r = t_f = 3.0 \ ns)$

		V _{CC} *	Guarantee	Guaranteed Limits	
Symbol	Parameter	V	25 °C	-40°C to 85°C	Unit
t_{su}	Minimum Setup Time, Data to Clock (Figure 3)	3.3 5.0	6.5 5.0	7.0 5.5	ns
t_h	Minimum Hold Time, Clock to Data (Figure 3)	3.3 5.0	3.0 3.0	3.0 3.0	ns
t _w	Minimum Pulse Width, Reset (Figure 2)	3.3 5.0	5.5 5.0	7.0 5.0	ns
t _w	Minimum Pulse Width, Clock (Figure 1)	3.3 5.0	5.5 5.0	7.0 5.0	ns
t _{rec}	Minimum Recovery Time, Reset to Clock (Figure 2)	3.3 5.0	2.5 2.0	2.5 2.0	ns

^{*}Voltage Range 3.3 V is 3.3 V ± 0.3 V Voltage Range 5.0 V is 5.0 V ± 0.5 V



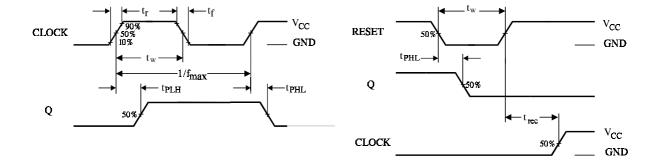


Figure 1. Switching Waveforms

Figure 2. Switching Waveforms

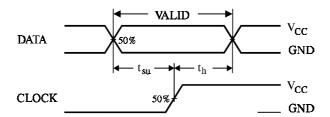


Figure 3. Switching Waveforms

EXPANDED LOGIC DIAGRAM

